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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	80MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	3.3V
Operating Temperature	0°C ~ 95°C (TA)
Security Features	-
Package / Case	256-BGA
Supplier Device Package	256-PBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/xpc850dezt80bu

- Separate power supply input to operate internal logic at 2.2 V when operating at or below 25 MHz
- Can be dynamically shifted between high frequency (3.3 V internal) and low frequency (2.2 V internal) operation
- Debug interface
 - Eight comparators: four operate on instruction address, two operate on data address, and two operate on data
 - The MPC850 can compare using the =, ≠, <, and > conditions to generate watchpoints
 - Each watchpoint can generate a breakpoint internally
- 3.3-V operation with 5-V TTL compatibility on all general purpose I/O pins.

3 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC850. [Table 2](#) provides the maximum ratings.

Table 2. Maximum Ratings

(GND = 0V)

Rating	Symbol	Value	Unit
Supply voltage	VDDH	-0.3 to 4.0	V
	VDDL	-0.3 to 4.0	V
	KAPWR	-0.3 to 4.0	V
	VDDSYN	-0.3 to 4.0	V
Input voltage ¹	V _{in}	GND-0.3 to VDDH + 2.5 V	V
Junction temperature ²	T _j	0 to 95 (standard) -40 to 95 (extended)	°C
Storage temperature range	T _{stg}	-55 to +150	°C

¹ Functional operating conditions are provided with the DC electrical specifications in [Table 5](#). Absolute maximum ratings are stress ratings only; functional operation at the maxima is not guaranteed. Stress beyond those listed may affect device reliability or cause permanent damage to the device.

CAUTION: All inputs that tolerate 5 V cannot be more than 2.5 V greater than the supply voltage. This restriction applies to power-up and normal operation (that is, if the MPC850 is unpowered, voltage greater than 2.5 V must not be applied to its inputs).

² The MPC850, a high-frequency device in a BGA package, does not provide a guaranteed maximum ambient temperature. Only maximum junction temperature is guaranteed. It is the responsibility of the user to consider power dissipation and thermal management. Junction temperature ratings are the same regardless of frequency rating of the device.

This device contains circuitry protecting against damage due to high-static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V_{CC}). [Table 3](#) provides the package thermal characteristics for the MPC850.

Table 5. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input low voltage	VIL	GND	0.8	V
EXTAL, EXTCLK input high voltage	VIHC	0.7*(VCC)	VCC+0.3	V
Input leakage current, Vin = 5.5 V (Except TMS, $\overline{\text{TRST}}$, DSCK and DSDI pins)	I _{in}	—	100	μA
Input leakage current, Vin = 3.6V (Except TMS, $\overline{\text{TRST}}$, DSCK and DSDI pins)	I _{in}	—	10	μA
Input leakage current, Vin = 0V (Except TMS, $\overline{\text{TRST}}$, DSCK and DSDI pins)	I _{in}	—	10	μA
Input capacitance	C _{in}	—	20	pF
Output high voltage, IOH = -2.0 mA, VDDH = 3.0V except XTAL, XFC, and open-drain pins	VOH	2.4	—	V
Output low voltage CLKOUT ³ IOL = 3.2 mA ¹ IOL = 5.3 mA ² IOL = 7.0 mA PA[14]/ $\overline{\text{USBOE}}$, PA[12]/TXD2 IOL = 8.9 mA $\overline{\text{TS}}$, $\overline{\text{TA}}$, $\overline{\text{TEA}}$, $\overline{\text{BI}}$, $\overline{\text{BB}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$	VOL	—	0.5	V

¹ A[6:31], TSIZ0/ $\overline{\text{REG}}$, TSIZ1, D[0:31], DP[0:3]/ $\overline{\text{IRQ}}[3:6]$, RD/ $\overline{\text{WR}}$, BURST, RSV/ $\overline{\text{IRQ2}}$, IP_B[0:1]/IWP[0:1]/VFLS[0:1], IP_B2/ $\overline{\text{IOIS16_B/AT2}}$, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/ $\overline{\text{PTR/AT3}}$, PA[15]/ $\overline{\text{USBRXD}}$, PA[13]/RXD2, PA[9]/L1TXDA/SMRXD2, PA[8]/L1RXDA/SMTXD2, PA[7]/CLK1/TIN1/L1RCLKA/BRGO1, PA[6]/CLK2/TOUT1/TIN3, PA[5]/CLK3/TIN2/L1TCLKA/BRGO2, PA[4]/CLK4/TOUT2/TIN4, PB[31]/SPISEL, PB[30]/SPICLK/TXD3, PB[29]/SPIMOSI /RXD3, PB[28]/SPIMISO/BRGO3, PB[27]/I2CSDA/BRGO1, PB[26]/I2CSCL/BRGO2, PB[25]/SMTXD1/TXD3, PB[24]/SMRXD1/RXD3, PB[23]/SMSYN1/SDACK1, PB[22]/SMSYN2/SDACK2, PB[19]/L1ST1, PB[18]/RTS2/L1ST2, PB[17]/L1ST3, PB[16]/L1RQa/L1ST4, PC[15]/DREQ0/L1ST5, PC[14]/DREQ1/RTS2/L1ST6, PC[13]/L1ST7/RTS3, PC[12]/L1RQa/L1ST8, PC[11]/ $\overline{\text{USBRXP}}$, PC[10]/TGATE1/ $\overline{\text{USBRXN}}$, PC[9]/CTS2, PC[8]/CD2/TGATE1, PC[7]/ $\overline{\text{USBTXP}}$, PC[6]/ $\overline{\text{USBTXN}}$, PC[5]/CTS3/L1TSYNCA/SDACK1, PC[4]/CD3/L1RSYNCA, PD[15], PD[14], PD[13], PD[12], PD[11], PD[10], PD[9], PD[8], PD[7], PD[6], PD[5], PD[4], PD[3]

² $\overline{\text{BDIP/GPL_B5}}$, $\overline{\text{BR}}$, $\overline{\text{BG}}$, FRZ/ $\overline{\text{IRQ6}}$, $\overline{\text{CS}}[0:5]$, $\overline{\text{CS6/CE1_B}}$, $\overline{\text{CS7/CE2_B}}$, $\overline{\text{WE0/BS_AB0/IORD}}$, $\overline{\text{WE1/BS_AB1/IOWR}}$, $\overline{\text{WE2/BS_AB2/PCOE}}$, $\overline{\text{WE3/BS_AB3/PCWE}}$, $\overline{\text{GPL_A0/GPL_B0}}$, $\overline{\text{OE/GPL_A1/GPL_B1}}$, $\overline{\text{GPL_A2:3/GPL_B2:3/CS2:3}}$, UPWAITA/ $\overline{\text{GPL_A4/AS}}$, UPWAITB/ $\overline{\text{GPL_B4}}$, $\overline{\text{GPL_A5}}$, $\overline{\text{ALE_B/DSCK/AT1}}$, OP2/MODCK1/STS, OP3/MODCK2/SDO

³ The MPC850 IBIS model must be used to accurately model the behavior of the Clkout output driver for the full and half drive setting. Due to the nature of the Clkout output buffer, IOH and IOL for Clkout should be extracted from the IBIS model at any output voltage level.

5 Power Considerations

The average chip-junction temperature, T_J, in °C can be obtained from the equation:

$$T_J = T_A + (P_D \cdot \theta_{JA})(1)$$

where

$$T_A = \text{Ambient temperature, } ^\circ\text{C}$$

Table 6. Bus Operation Timing ¹ (continued)

Num	Characteristic	50 MHz		66 MHz		80 MHz		FFACT	Cap Load (default 50 pF)	Unit
		Min	Max	Min	Max	Min	Max			
B9	CLKOUT to A[6–31] RD/WR, BURST, D[0–31], DP[0–3], TSIZ[0–1], REG, RSV, AT[0–3], PTR high-Z	5.00	11.75	7.58	14.33	6.25	13.00	0.250	50.00	ns
B11	CLKOUT to $\overline{\text{TS}}$, $\overline{\text{BB}}$ assertion	5.00	11.00	7.58	13.58	6.25	12.25	0.250	50.00	ns
B11a	CLKOUT to $\overline{\text{TA}}$, $\overline{\text{BI}}$ assertion, (When driven by the memory controller or PCMCIA interface)	2.50	9.25	2.50	9.25	2.50	9.25	—	50.00	ns
B12	CLKOUT to $\overline{\text{TS}}$, $\overline{\text{BB}}$ negation	5.00	11.75	7.58	14.33	6.25	13.00	0.250	50.00	ns
B12a	CLKOUT to $\overline{\text{TA}}$, $\overline{\text{BI}}$ negation (when driven by the memory controller or PCMCIA interface)	2.50	11.00	2.50	11.00	2.50	11.00	—	50.00	ns
B13	CLKOUT to $\overline{\text{TS}}$, $\overline{\text{BB}}$ high-Z	5.00	19.00	7.58	21.58	6.25	20.25	0.250	50.00	ns
B13a	CLKOUT to $\overline{\text{TA}}$, $\overline{\text{BI}}$ high-Z, (when driven by the memory controller or PCMCIA interface)	2.50	15.00	2.50	15.00	2.50	15.00	—	50.00	ns
B14	CLKOUT to $\overline{\text{TEA}}$ assertion	2.50	10.00	2.50	10.00	2.50	10.00	—	50.00	ns
B15	CLKOUT to $\overline{\text{TEA}}$ high-Z	2.50	15.00	2.50	15.00	2.50	15.00	—	50.00	ns
B16	$\overline{\text{TA}}$, $\overline{\text{BI}}$ valid to CLKOUT (setup time) ⁵	9.75	—	9.75	—	9.75	—	—	50.00	ns
B16a	$\overline{\text{TEA}}$, $\overline{\text{KR}}$, $\overline{\text{RETRY}}$, valid to CLKOUT (setup time) ⁵	10.00	—	10.00	—	10.00	—	—	50.00	ns
B16b	$\overline{\text{BB}}$, $\overline{\text{BG}}$, $\overline{\text{BR}}$ valid to CLKOUT (setup time) ⁶	8.50	—	8.50	—	8.50	—	—	50.00	ns
B17	CLKOUT to $\overline{\text{TA}}$, $\overline{\text{TEA}}$, $\overline{\text{BI}}$, $\overline{\text{BB}}$, $\overline{\text{BG}}$, $\overline{\text{BR}}$ valid (Hold time). ⁵	1.00	—	1.00	—	1.00	—	—	50.00	ns
B17a	CLKOUT to $\overline{\text{KR}}$, $\overline{\text{RETRY}}$, except $\overline{\text{TEA}}$ valid (hold time)	2.00	—	2.00	—	2.00	—	—	50.00	ns
B18	D[0–31], DP[0–3] valid to CLKOUT rising edge (setup time) ⁷	6.00	—	6.00	—	6.00	—	—	50.00	ns
B19	CLKOUT rising edge to D[0–31], DP[0–3] valid (hold time) ⁷	1.00	—	1.00	—	1.00	—	—	50.00	ns
B20	D[0–31], DP[0–3] valid to CLKOUT falling edge (setup time) ⁸	4.00	—	4.00	—	4.00	—	—	50.00	ns
B21	CLKOUT falling edge to D[0–31], DP[0–3] valid (hold time) ⁸	2.00	—	2.00	—	2.00	—	—	—	—

Table 6. Bus Operation Timing ¹ (continued)

Num	Characteristic	50 MHz		66 MHz		80 MHz		FFACT	Cap Load (default 50 pF)	Unit
		Min	Max	Min	Max	Min	Max			
B31	CLKOUT falling edge to \overline{CS} valid - as requested by control bit CST4 in the corresponding word in the UPM	1.50	6.00	1.50	6.00	1.50	6.00	—	50.00	ns
B31a	CLKOUT falling edge to \overline{CS} valid - as requested by control bit CST1 in the corresponding word in the UPM	5.00	12.00	8.00	14.00	6.00	13.00	0.250	50.00	ns
B31b	CLKOUT rising edge to \overline{CS} valid - as requested by control bit CST2 in the corresponding word in the UPM	1.50	8.00	1.50	8.00	1.50	8.00	—	50.00	ns
B31c	CLKOUT rising edge to \overline{CS} valid - as requested by control bit CST3 in the corresponding word in the UPM	5.00	12.00	8.00	14.00	6.00	13.00	0.250	50.00	ns
B31d	CLKOUT falling edge to \overline{CS} valid - as requested by control bit CST1 in the corresponding word in the UPM EBDF = 1	9.00	14.00	13.00	18.00	11.00	16.00	0.375	50.00	ns
B32	CLKOUT falling edge to \overline{BS} valid - as requested by control bit BST4 in the corresponding word in the UPM	1.50	6.00	1.50	6.00	1.50	6.00	—	50.00	ns
B32a	CLKOUT falling edge to \overline{BS} valid - as requested by control bit BST1 in the corresponding word in the UPM, EBDF = 0	5.00	12.00	8.00	14.00	6.00	13.00	0.250	50.00	ns
B32b	CLKOUT rising edge to \overline{BS} valid - as requested by control bit BST2 in the corresponding word in the UPM	1.50	8.00	1.50	8.00	1.50	8.00	—	50.00	ns
B32c	CLKOUT rising edge to \overline{BS} valid - as requested by control bit BST3 in the corresponding word in the UPM	5.00	12.00	8.00	14.00	6.00	13.00	0.250	50.00	ns
B32d	CLKOUT falling edge to \overline{BS} valid - as requested by control bit BST1 in the corresponding word in the UPM, EBDF = 1	9.00	14.00	13.00	18.00	11.00	16.00	0.375	50.00	ns
B33	CLKOUT falling edge to GPL valid - as requested by control bit GxT4 in the corresponding word in the UPM	1.50	6.00	1.50	6.00	1.50	6.00	—	50.00	ns

Table 6. Bus Operation Timing ¹ (continued)

Num	Characteristic	50 MHz		66 MHz		80 MHz		FFACTOR	Cap Load (default 50 pF)	Unit
		Min	Max	Min	Max	Min	Max			
B42	CLKOUT rising edge to \overline{TS} valid (hold time)	2.00	—	2.00	—	2.00	—	—	50.00	ns
B43	\overline{AS} negation to memory controller signals negation	—	TBD	—	TBD	TBD	—	—	50.00	ns

¹ The minima provided assume a 0 pF load, whereas maxima assume a 50pF load. For frequencies not marked on the part, new bus timing must be calculated for all frequency-dependent AC parameters. Frequency-dependent AC parameters are those with an entry in the FFactor column. AC parameters without an FFactor entry do not need to be calculated and can be taken directly from the frequency column corresponding to the frequency marked on the part. The following equations should be used in these calculations.

For a frequency F, the following equations should be applied to each one of the above parameters:

For minima:

$$D = \frac{\text{FFACTOR} \times 1000}{F} + (D_{50} - 20 \times \text{FFACTOR})$$

For maxima:

$$D = \frac{\text{FFACTOR} \times 1000}{F} + (D_{50} - 20 \times \text{FFACTOR}) + 1\text{ns}(\text{CAP LOAD} - 50) / 10$$

where:

D is the parameter value to the frequency required in ns

F is the operation frequency in MHz

D₅₀ is the parameter value defined for 50 MHz

CAP LOAD is the capacitance load on the signal in question.

FFACTOR is the one defined for each of the parameters in the table.

² Phase and frequency jitter performance results are valid only if the input jitter is less than the prescribed value.

³ If the rate of change of the frequency of EXTAL is slow (i.e. it does not jump between the minimum and maximum values in one cycle) or the frequency of the jitter is fast (i.e., it does not stay at an extreme value for a long time) then the maximum allowed jitter on EXTAL can be up to 2%.

⁴ The timing for \overline{BR} output is relevant when the MPC850 is selected to work with external bus arbiter. The timing for \overline{BG} output is relevant when the MPC850 is selected to work with internal bus arbiter.

⁵ The setup times required for \overline{TA} , \overline{TEA} , and \overline{BI} are relevant only when they are supplied by an external device (and not when the memory controller or the PCMCIA interface drives them).

⁶ The timing required for \overline{BR} input is relevant when the MPC850 is selected to work with the internal bus arbiter. The timing for \overline{BG} input is relevant when the MPC850 is selected to work with the external bus arbiter.

⁷ The D[0–31] and DP[0–3] input timings B20 and B21 refer to the rising edge of the CLKOUT in which the \overline{TA} input signal is asserted.

⁸ The D[0:31] and DP[0:3] input timings B20 and B21 refer to the falling edge of CLKOUT. This timing is valid only for read accesses controlled by chip-selects controlled by the UPM in the memory controller, for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.

⁹ The timing B30 refers to \overline{CS} when ACS = '00' and to $\overline{WE}[0:3]$ when CSNT = '0'.

¹⁰ The signal UPWAIT is considered asynchronous to CLKOUT and synchronized internally. The timings specified in B37 and B38 are specified to enable the freeze of the UPM output signals.

¹¹ The \overline{AS} signal is considered asynchronous to CLKOUT.

Figure 4 provides the timing for the synchronous output signals.

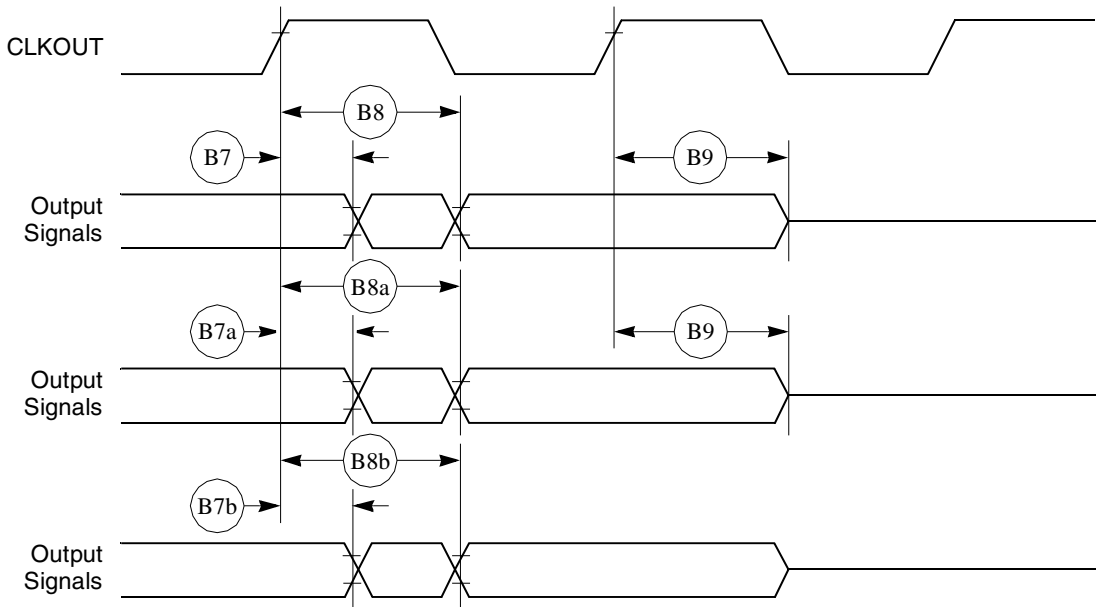


Figure 4. Synchronous Output Signals Timing

Figure 5 provides the timing for the synchronous active pull-up and open-drain output signals.

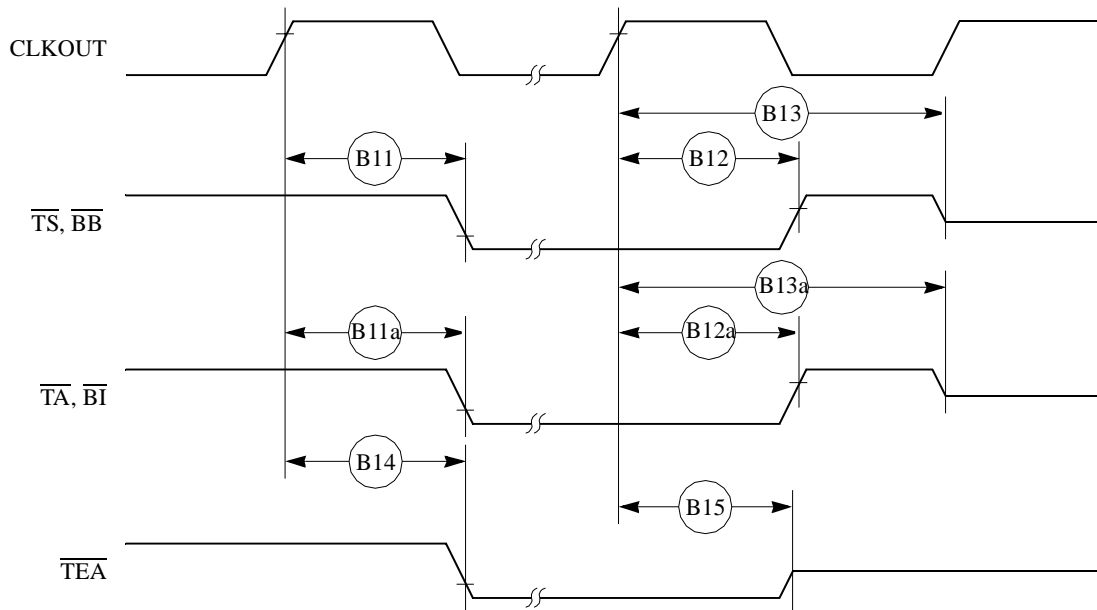


Figure 5. Synchronous Active Pullup and Open-Drain Outputs Signals Timing

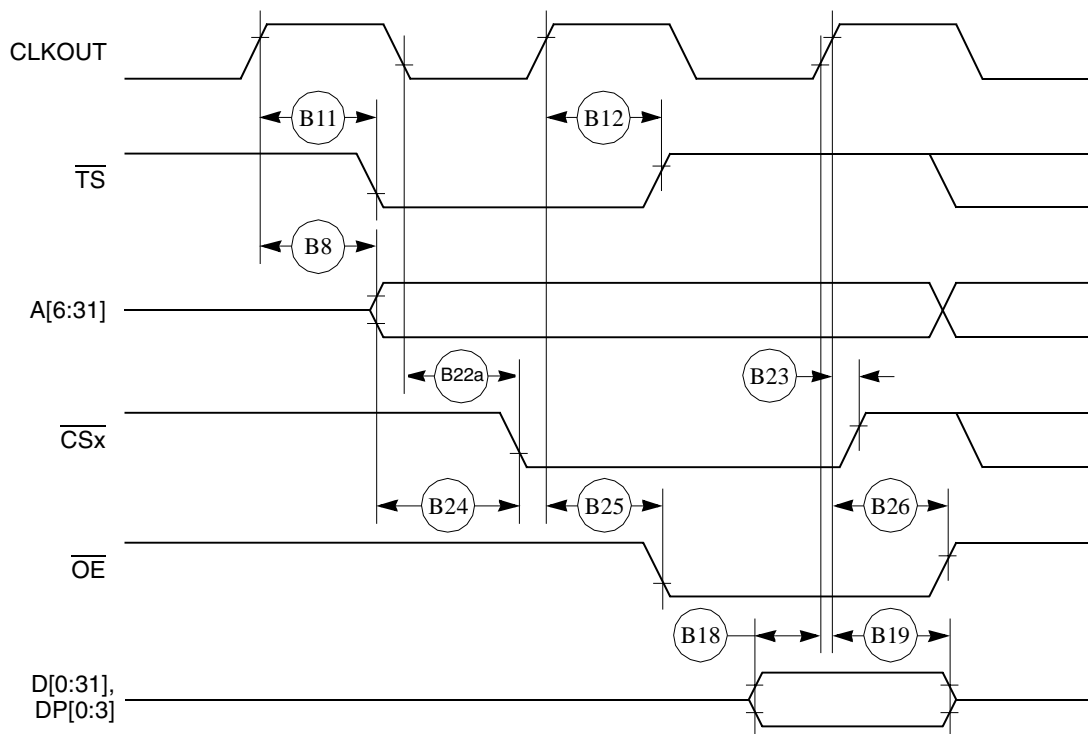


Figure 10. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 10)

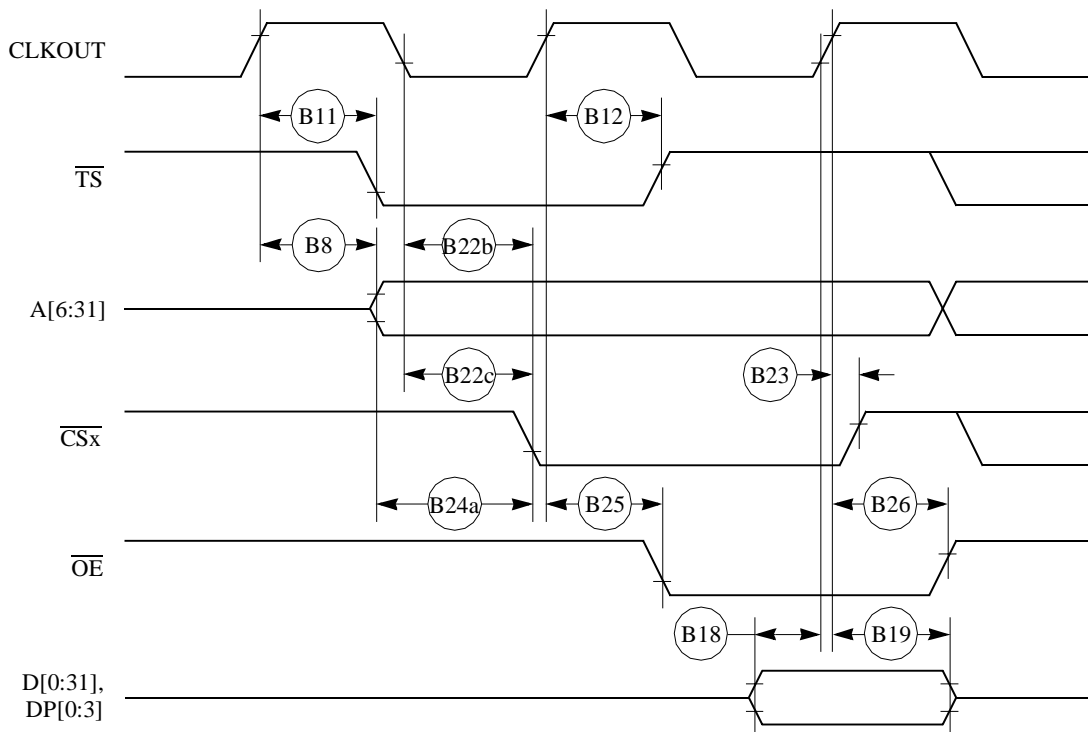


Figure 11. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 11)

Figure 13 through Figure 15 provide the timing for the external bus write controlled by various GPCM factors.

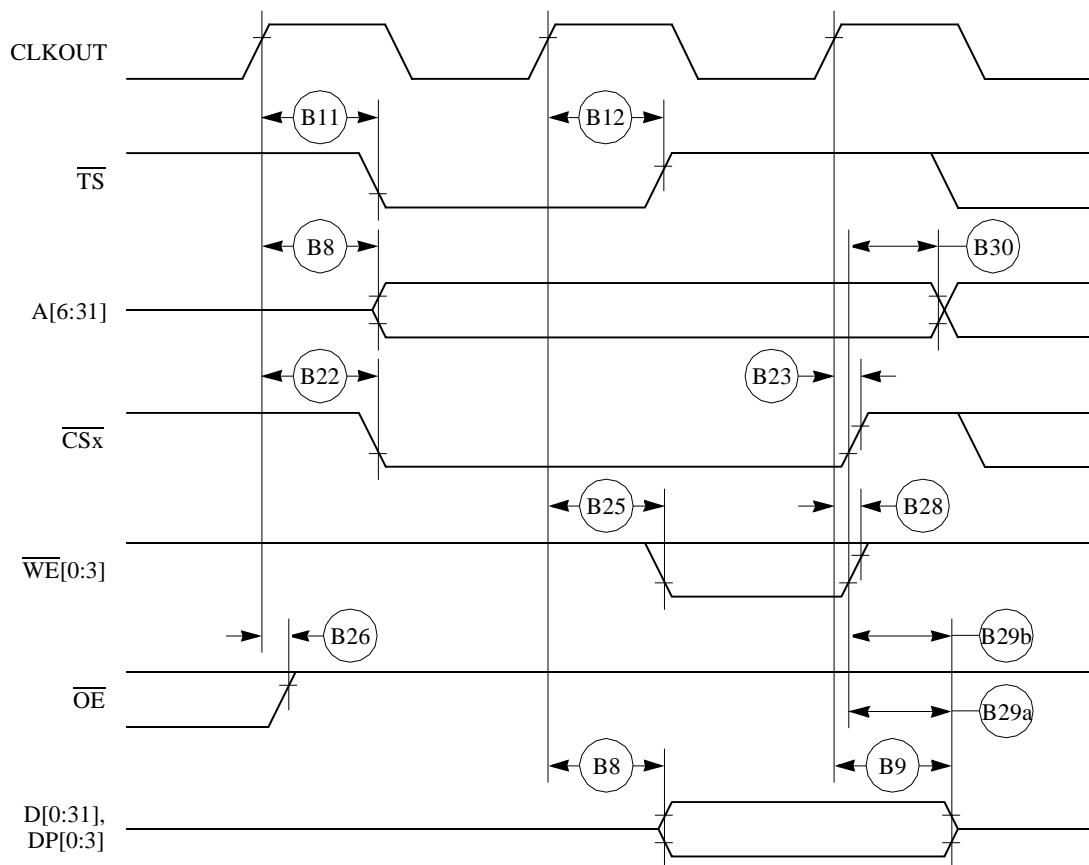


Figure 13. External Bus Write Timing (GPCM Controlled—TRLX = 0, CSNT = 0)

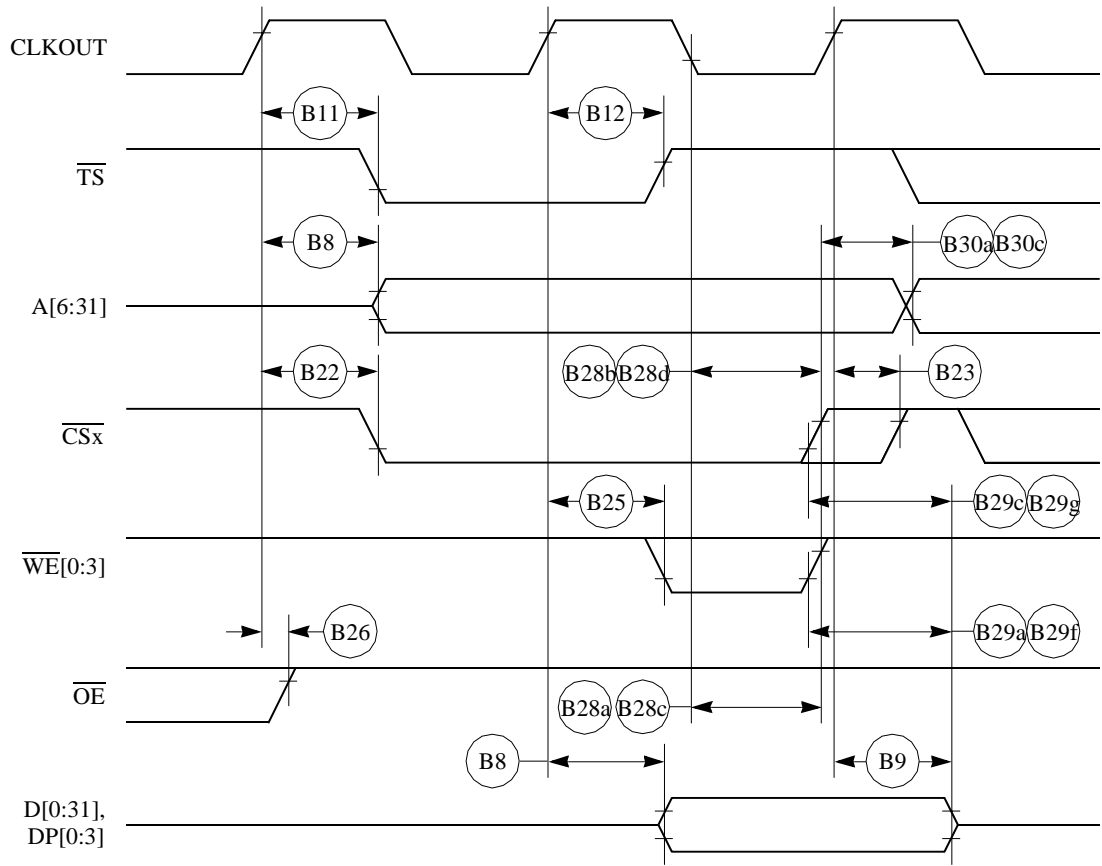


Figure 14. External Bus Write Timing (GPCM Controlled—TRLX = 0, CSNT = 1)

Figure 19 provides the timing for the synchronous external master access controlled by the GPCM.

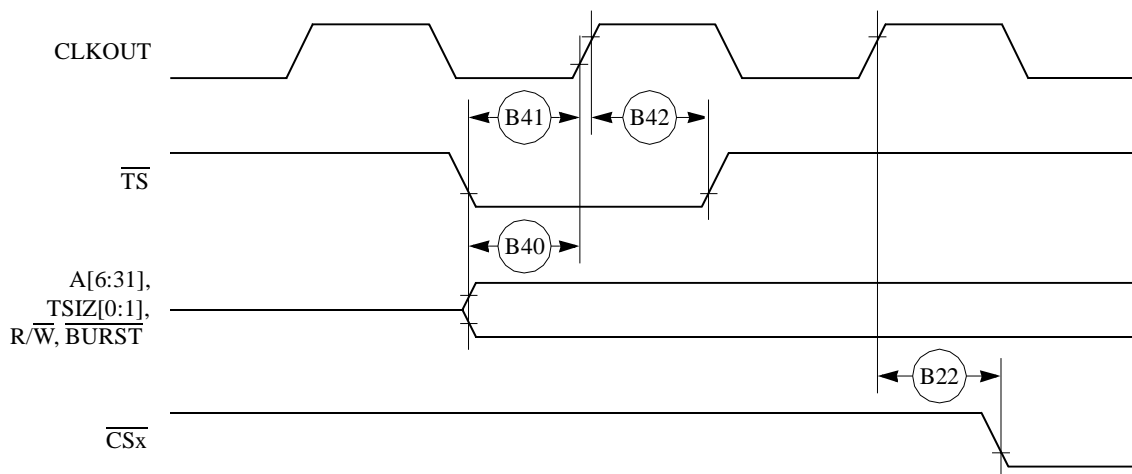


Figure 19. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 20 provides the timing for the asynchronous external master memory access controlled by the GPCM.

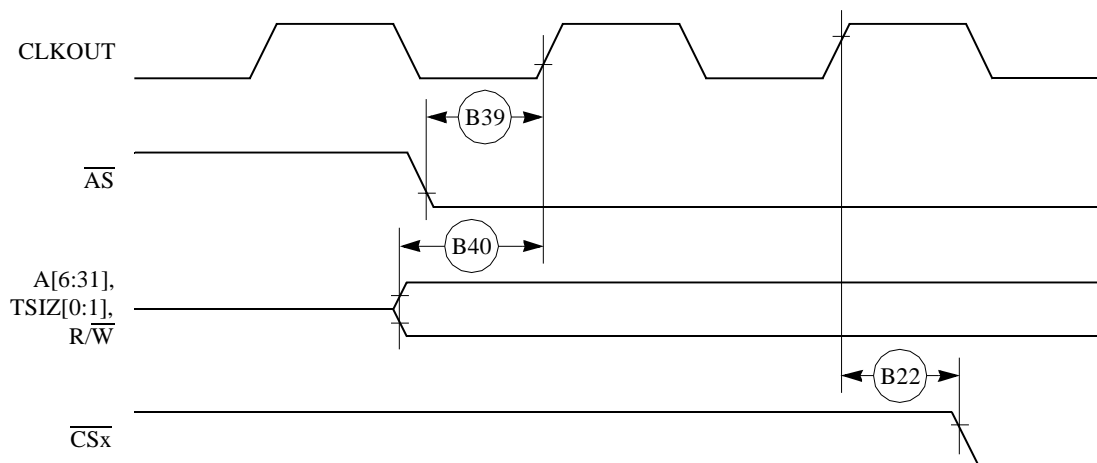


Figure 20. Asynchronous External Master Memory Access Timing (GPCM Controlled—ACS = 00)

Figure 21 provides the timing for the asynchronous external master control signals negation.

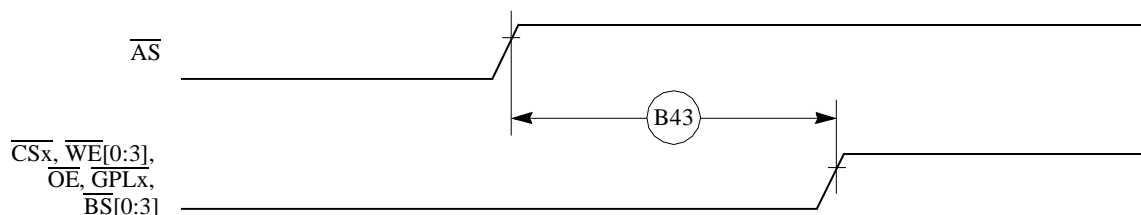


Figure 21. Asynchronous External Master—Control Signals Negation Timing

Table 7 provides interrupt timing for the MPC850.

Table 7. Interrupt Timing

Num	Characteristic ¹	50 MHz		66MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	
I39	$\overline{\text{IRQx}}$ valid to CLKOUT rising edge (set up time)	6.00	—	6.00	—	6.00	—	ns
I40	$\overline{\text{IRQx}}$ hold time after CLKOUT.	2.00	—	2.00	—	2.00	—	ns
I41	$\overline{\text{IRQx}}$ pulse width low	3.00	—	3.00	—	3.00	—	ns
I42	$\overline{\text{IRQx}}$ pulse width high	3.00	—	3.00	—	3.00	—	ns
I43	$\overline{\text{IRQx}}$ edge-to-edge time	80.00	—	121.0	—	100.0	—	ns

¹ The timings I39 and I40 describe the testing conditions under which the $\overline{\text{IRQ}}$ lines are tested when being defined as level sensitive. The $\overline{\text{IRQ}}$ lines are synchronized internally and do not have to be asserted or negated with reference to the CLKOUT.

The timings I41, I42, and I43 are specified to allow the correct function of the $\overline{\text{IRQ}}$ lines detection circuitry, and has no direct relation with the total system interrupt latency that the MPC850 is able to support

Figure 22 provides the interrupt detection timing for the external level-sensitive lines.

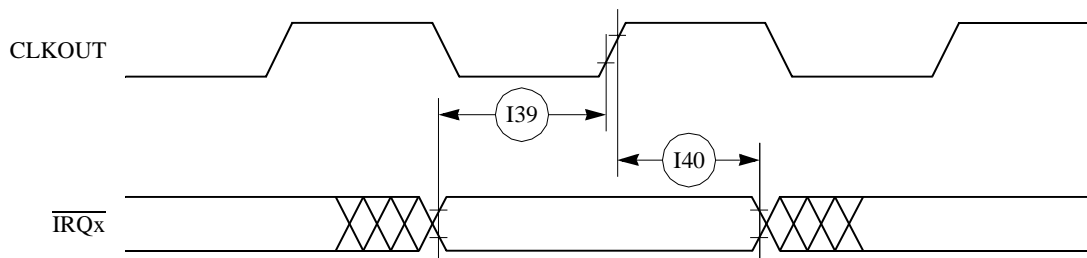


Figure 22. Interrupt Detection Timing for External Level Sensitive Lines

Figure 23 provides the interrupt detection timing for the external edge-sensitive lines.

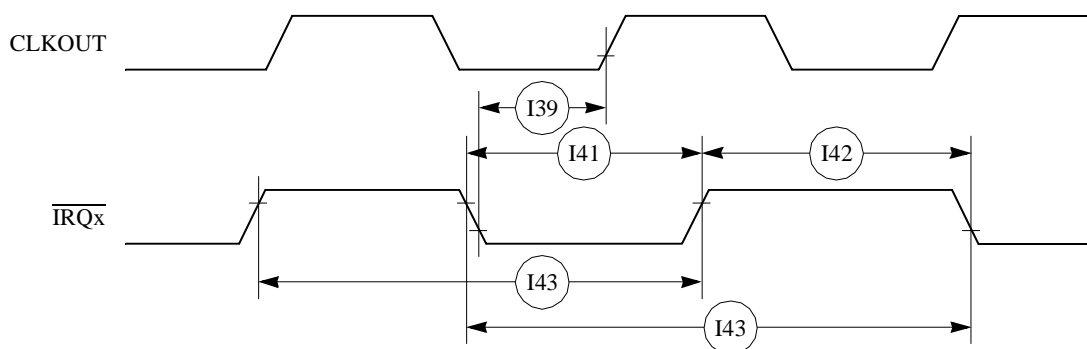


Figure 23. Interrupt Detection Timing for External Edge Sensitive Lines

Figure 25 provides the PCMCIA access cycle timing for the external bus write.

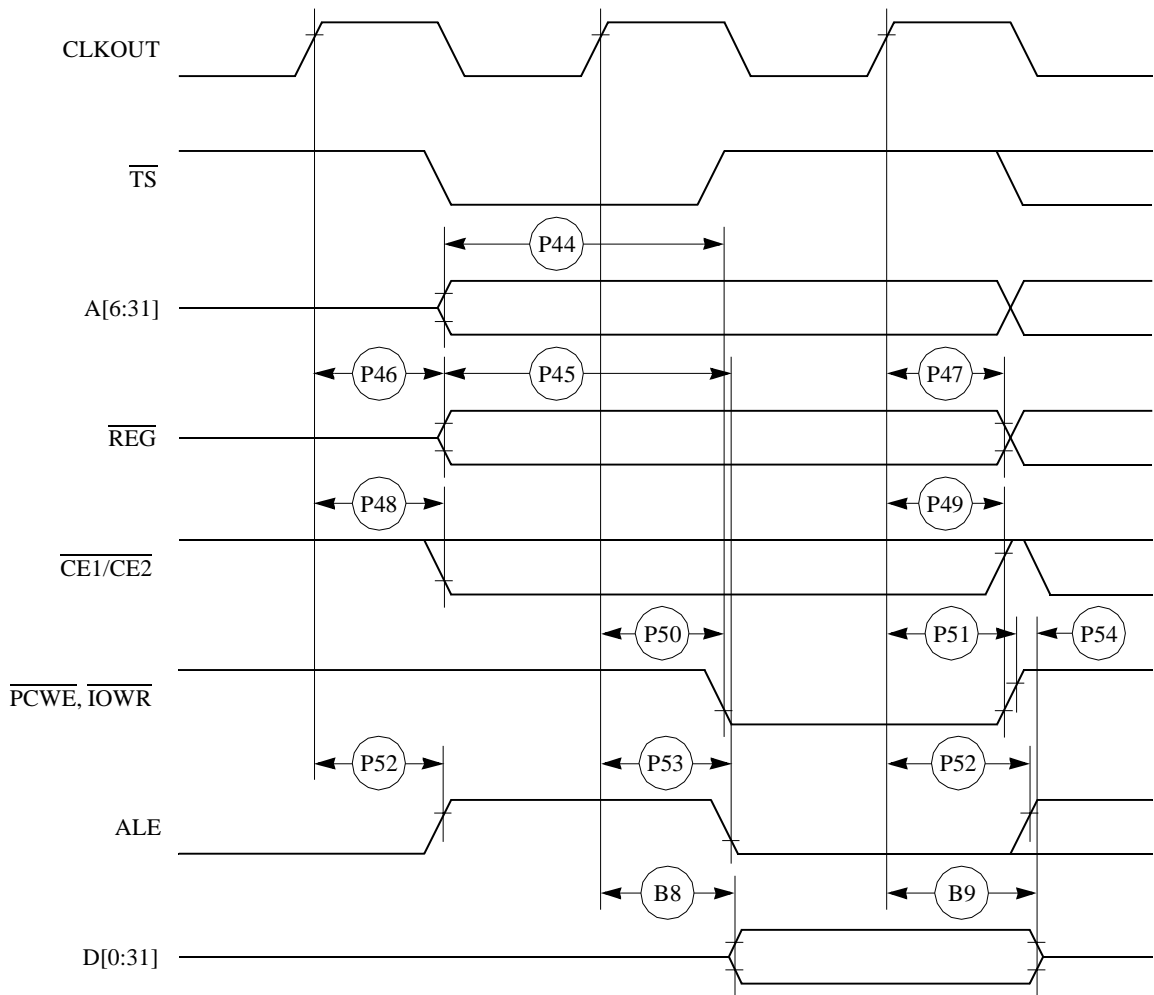


Figure 25. PCMCIA Access Cycles Timing External Bus Write

Figure 26 provides the PCMCIA WAIT signals detection timing.

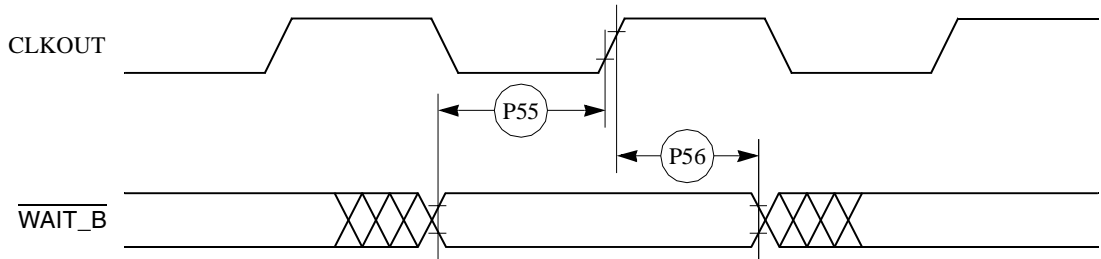


Figure 26. PCMCIA $\overline{\text{WAIT}}$ Signal Detection Timing

Figure 31 shows the reset timing for the data bus configuration.

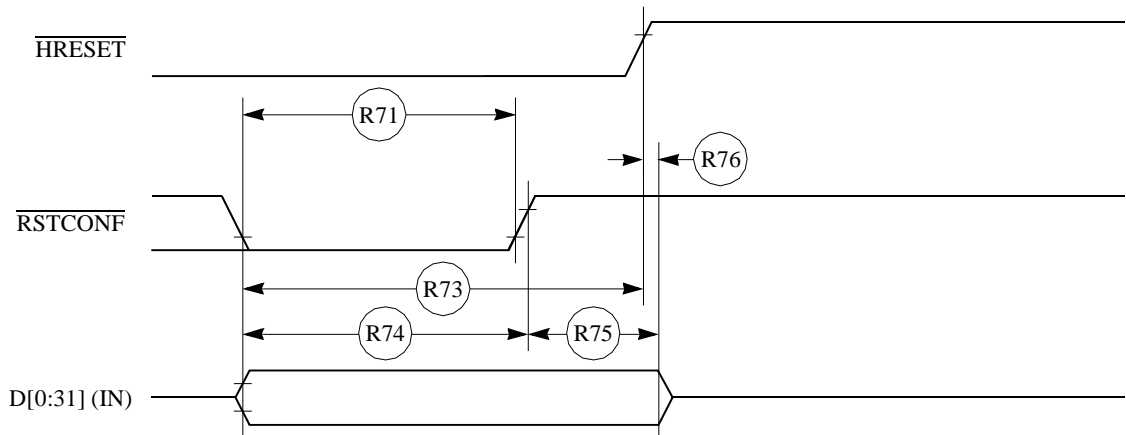


Figure 31. Reset Timing—Configuration from Data Bus

Figure 32 provides the reset timing for the data bus weak drive during configuration.

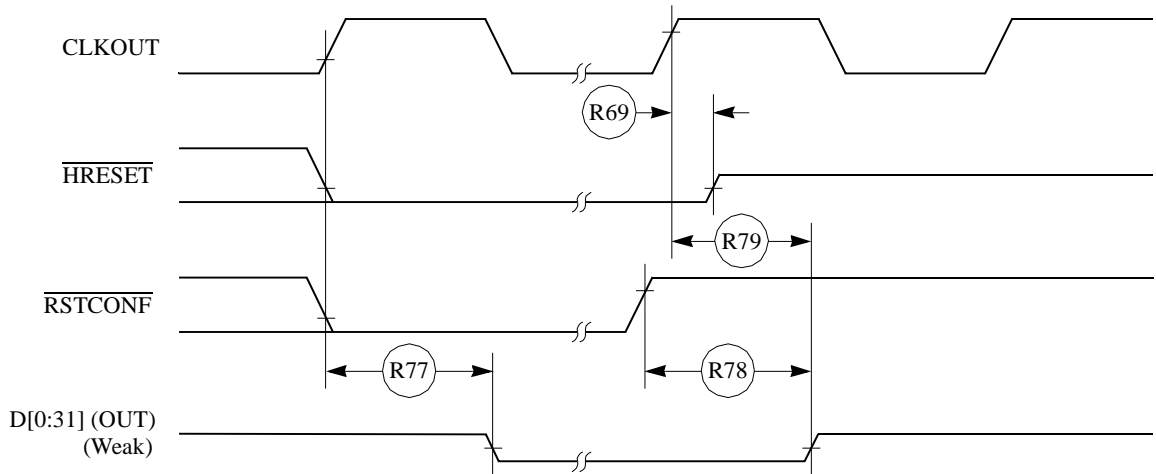


Figure 32. Reset Timing—Data Bus Weak Drive during Configuration

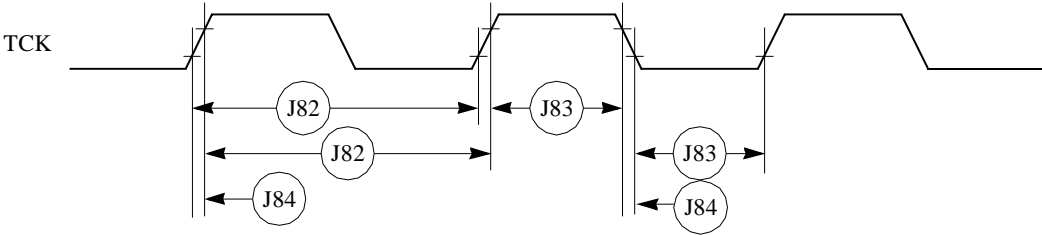


Figure 34. JTAG Test Clock Input Timing

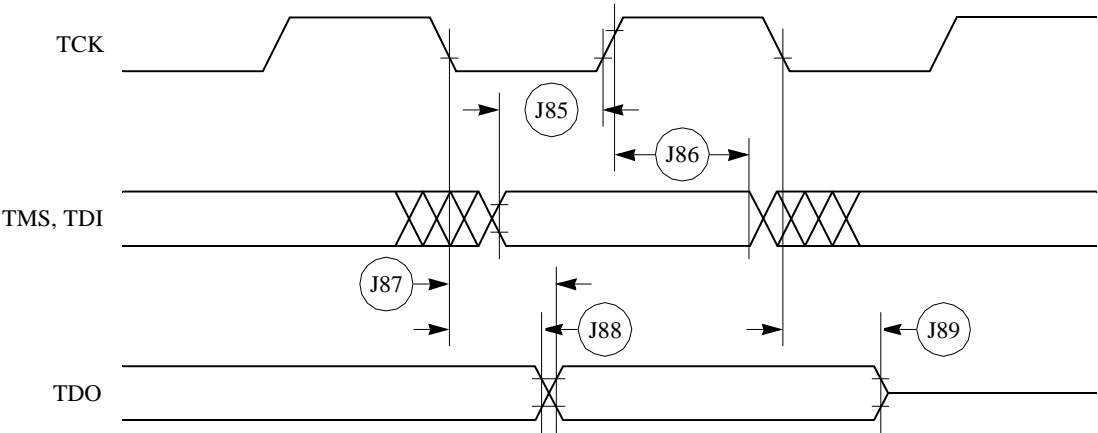


Figure 35. JTAG Test Access Port Timing Diagram

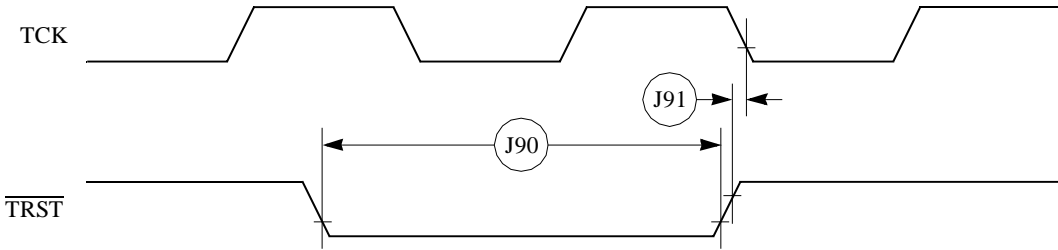


Figure 36. JTAG $\overline{\text{TRST}}$ Timing Diagram

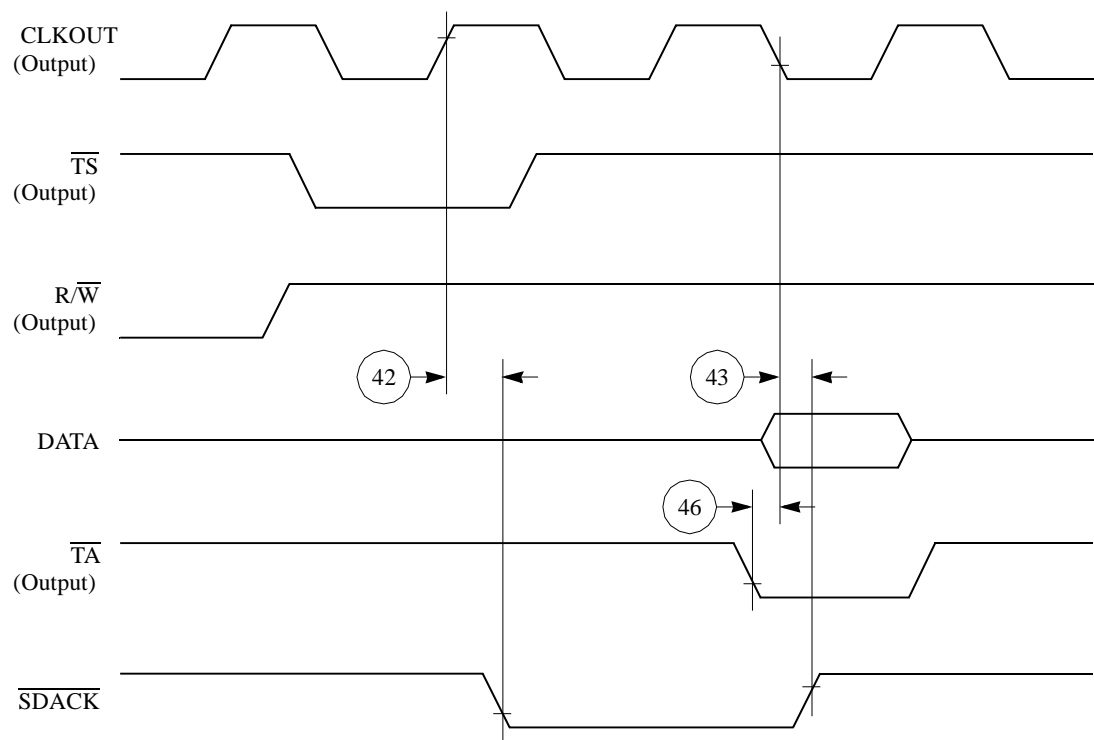


Figure 40. \overline{SDACK} Timing Diagram—Peripheral Write, \overline{TA} Sampled Low at the Falling Edge of the Clock

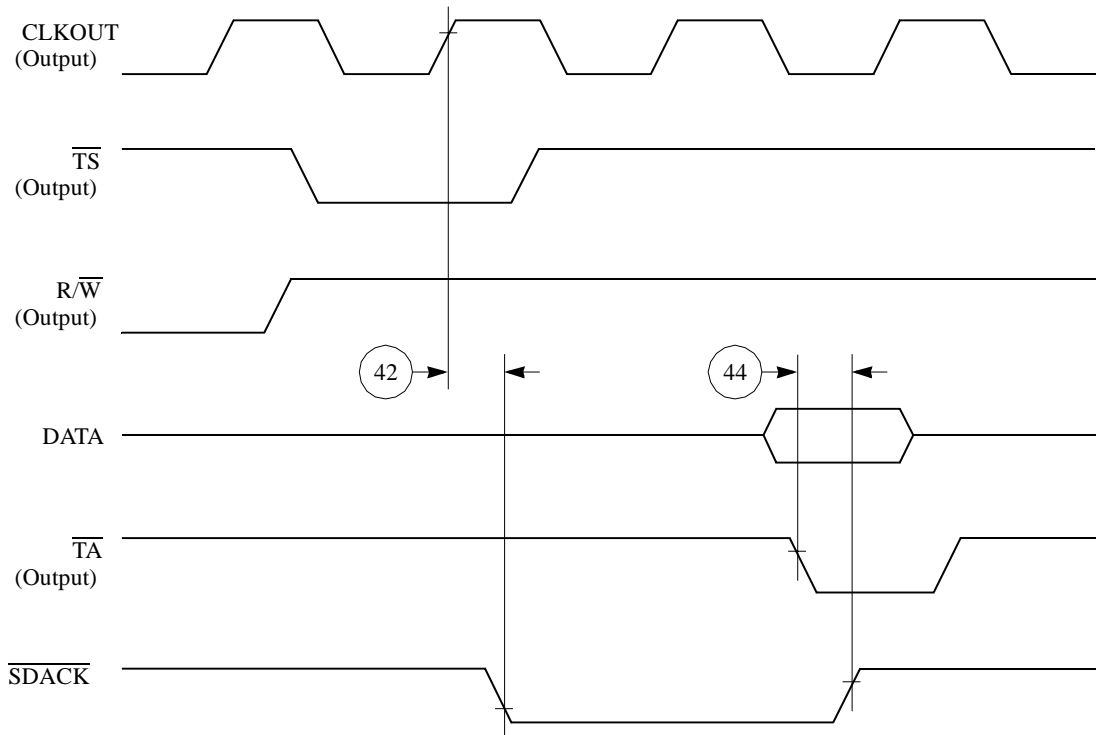


Figure 41. \overline{SDACK} Timing Diagram—Peripheral Write, \overline{TA} Sampled High at the Falling Edge of the Clock

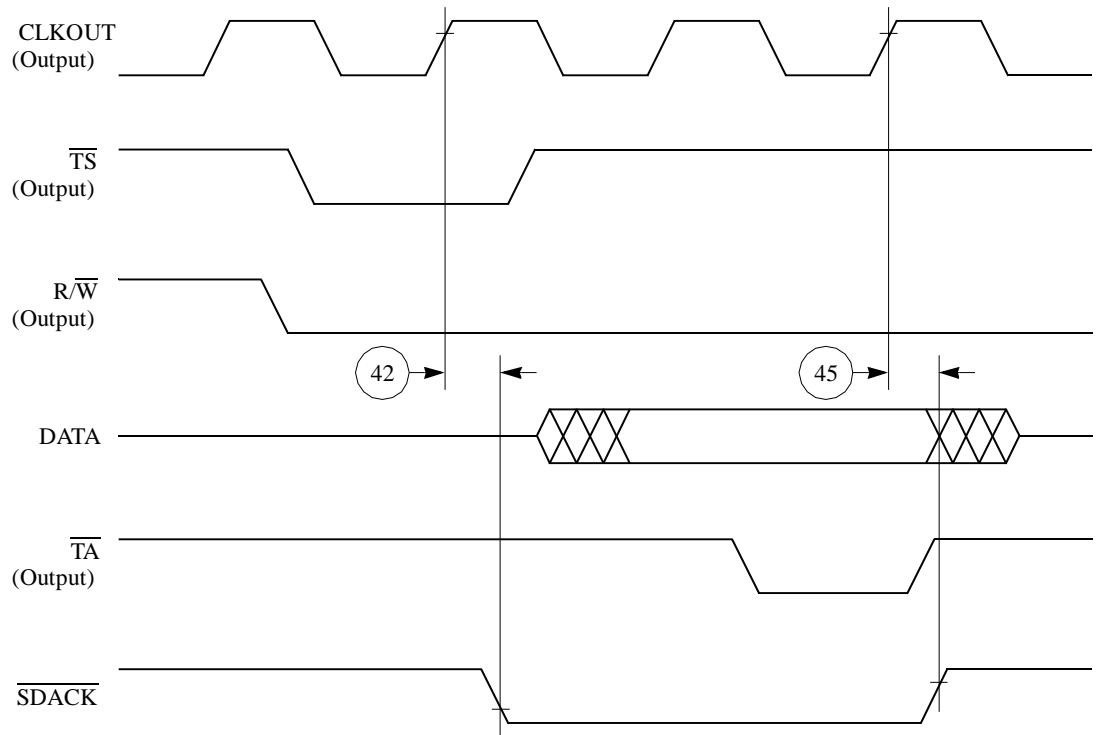


Figure 42. \overline{SDACK} Timing Diagram—Peripheral Read

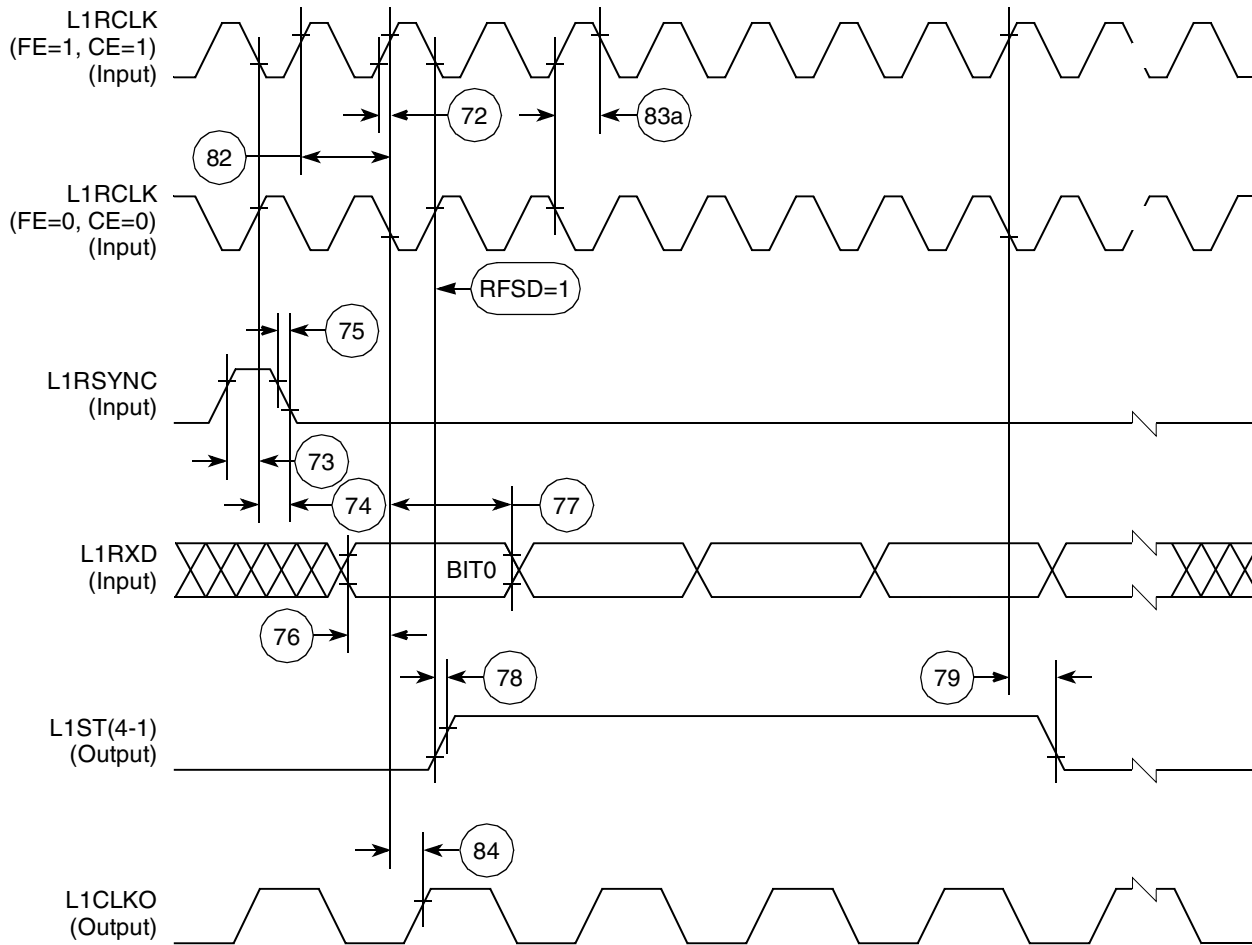


Figure 46. SI Receive Timing with Double-Speed Clocking (DSC = 1)

Figure 50 through Figure 52 show the NMSI timings.

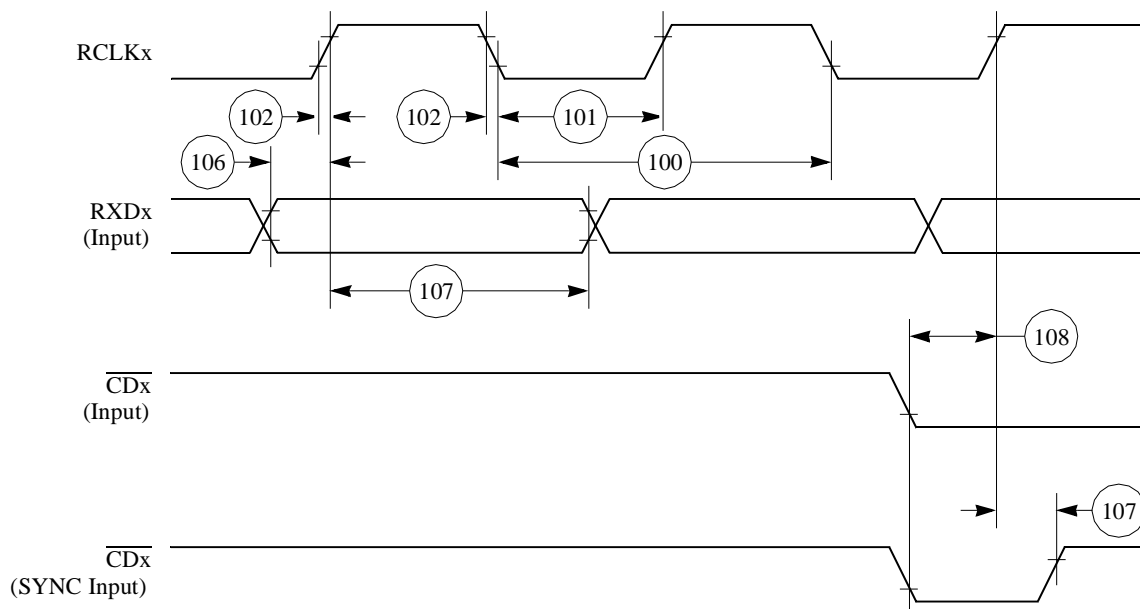


Figure 50. SCC NMSI Receive Timing Diagram

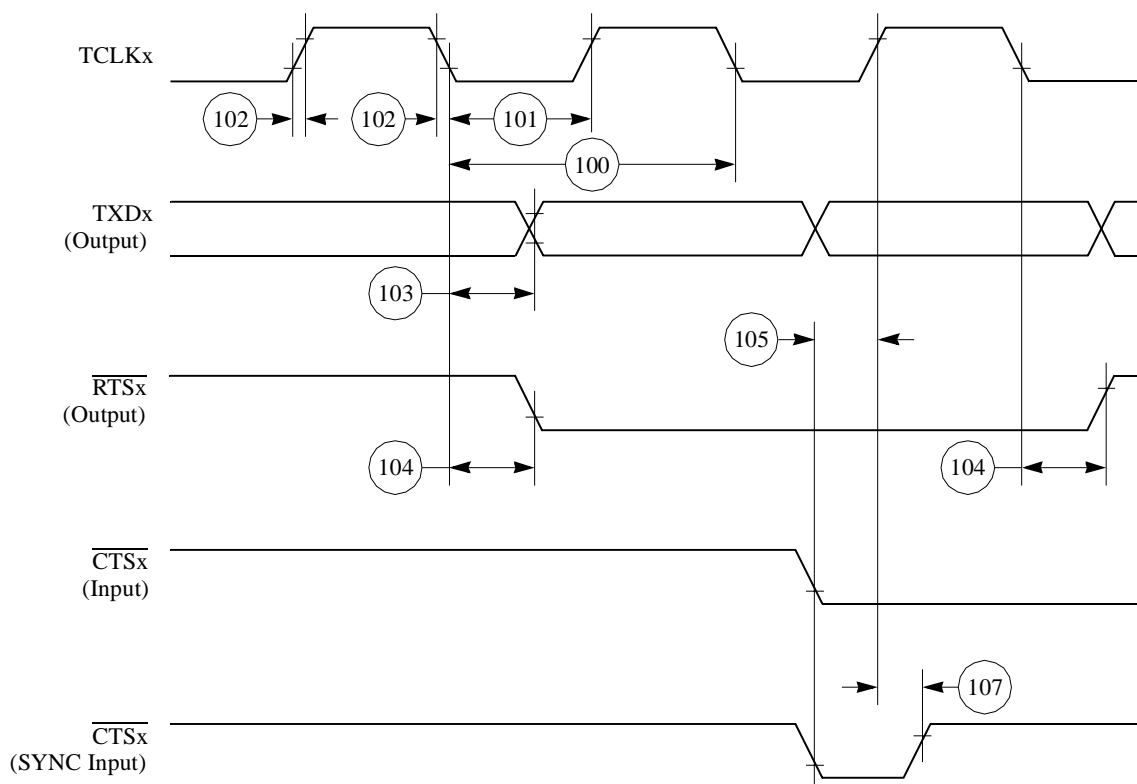
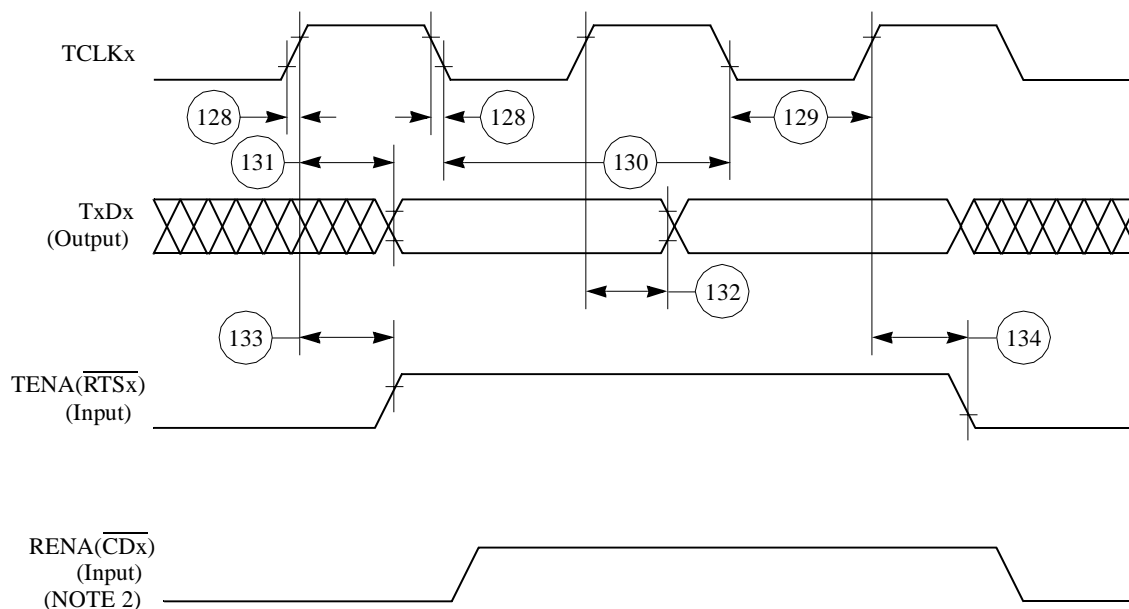


Figure 51. SCC NMSI Transmit Timing Diagram



NOTES:

1. Transmit clock invert (TCI) bit in GSMR is set.
2. If RENA is deasserted before TENA, or RENA is not asserted at all during transmit, then the CSL bit is set in the buffer descriptor at the end of the frame transmission.

Figure 55. Ethernet Transmit Timing Diagram

8.8 SMC Transparent AC Electrical Specifications

Figure 21 provides the SMC transparent timings as shown in Figure 56.

Table 21. Serial Management Controller Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
150	SMCLKx clock period ¹	100.00	—	ns
151	SMCLKx width low	50.00	—	ns
151a	SMCLKx width high	50.00	—	ns
152	SMCLKx rise/fall time	—	15.00	ns
153	SMTXDx active delay (from SMCLKx falling edge)	10.00	50.00	ns
154	SMRXDx/SMSYNx setup time	20.00	—	ns
155	SMRXDx/SMSYNx hold time	5.00	—	ns

¹ The ratio SyncCLK/SMCLKx must be greater or equal to 2/1.

Figure 65 shows the JEDEC package dimensions of the PBGA.

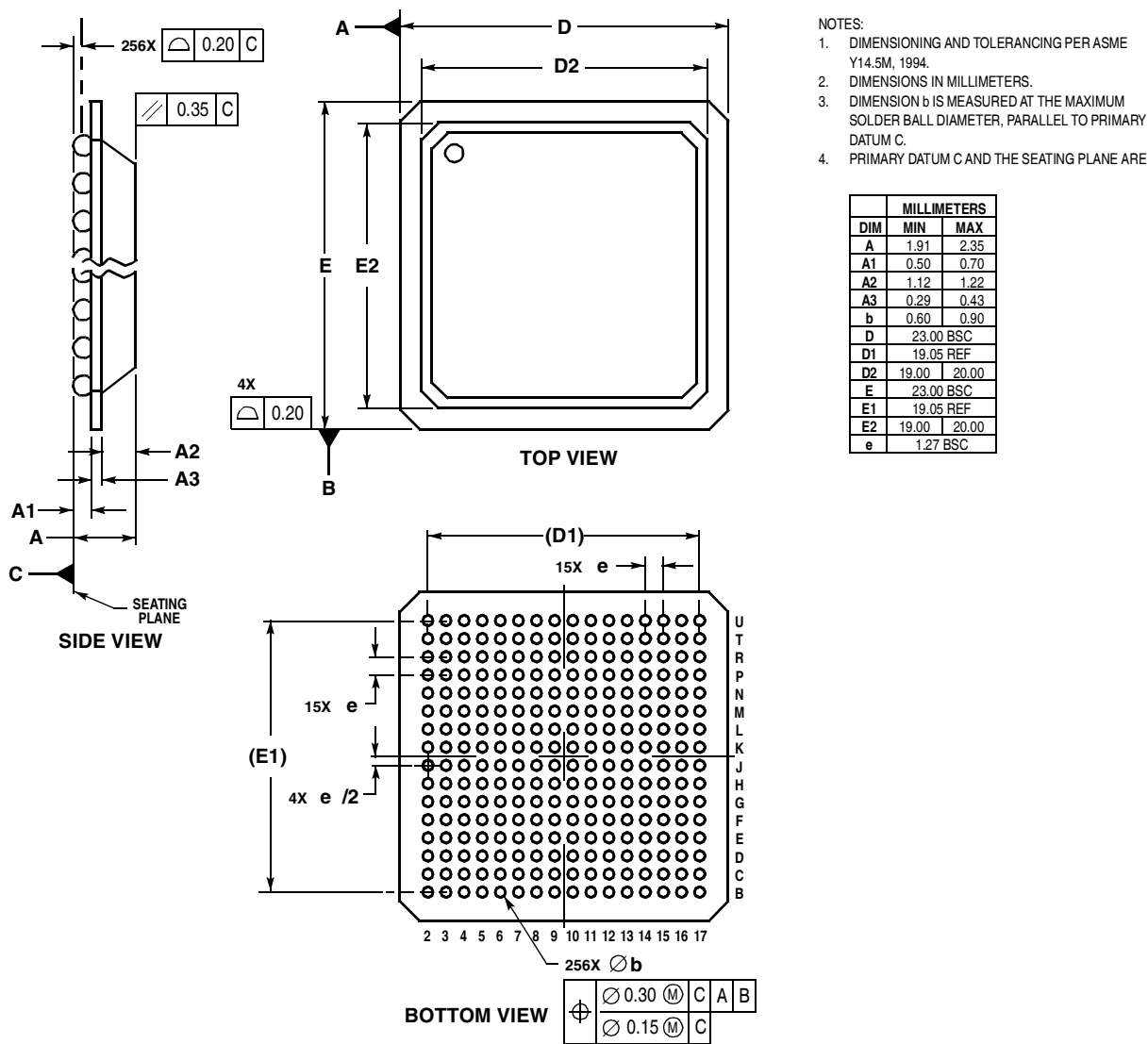


Figure 65. Package Dimensions for the Plastic Ball Grid Array (PBGA)—JEDEC Standard